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| Notice of References Cited | Application/Control No. 10/629,070 | Applicant(s)/Patent Under Reexamination SEILER ET AL. | |
| | Examiner Leslie J. Evanisko | Art Unit 2854 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------------|----------------|
| | A | US-2003/0084765 | 05-2003 | Elkotbi et al. | 83/13 |
| | B | US-5,123,316 | 06-1992 | Niedermaier et al. | 83/29 |
| | C | US-6,748,857 | 06-2004 | Seiler et al. | 101/226 |
| | D | US-2,214,593 | 09-1940 | LOUIS PITTALUGA; et. al. | 83/29 |
| | E | US-5,119,725 | 06-1992 | Okamura, Yuichi | 101/226 |
| | F | US-6,321,650 | 11-2001 | Ogawa et al. | 101/227 |
| | G | US-5,289,770 | 03-1994 | Hern, Joel C. | 101/226 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
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NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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